

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination KIM ET AL.	
		Examiner John P. Sheehan	Art Unit 1742	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0106615 A1	06-2003	Hirota et al.	148/101
*	B	US-2003/0047240 A1	03-2003	Honkura et al.	148/105
*	C	US-5,858,124 A	01-1999	Endo et al.	148/302
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	6-231925	06-1994	Japan	---	---
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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